



# STD9NM50N

N-channel 500 V, 0.73  $\Omega$ , 5 A MDmesh™II Power MOSFET  
in DPAK

## Features

| Order code | $V_{DS}@T_{JMAX}$ | $R_{DS(on)max.}$ | $I_D$ |
|------------|-------------------|------------------|-------|
| STD9NM50N  | 550 V             | < 0.79 $\Omega$  | 5 A   |

- 100% avalanche tested
- Low input capacitances and gate charge
- Low gate input resistance

## Applications

- Switching applications
- Automotive

## Description

These N-channel Power MOSFETs are developed using STMicroelectronics' revolutionary MDmesh™ technology, which associates the multiple drain process with the company's PowerMESH™ horizontal layout. These devices offer extremely low on-resistance, high dv/dt and excellent avalanche characteristics. Utilizing ST's proprietary strip technique, these Power MOSFETs boast an overall dynamic performance which is superior to similar products on the market.

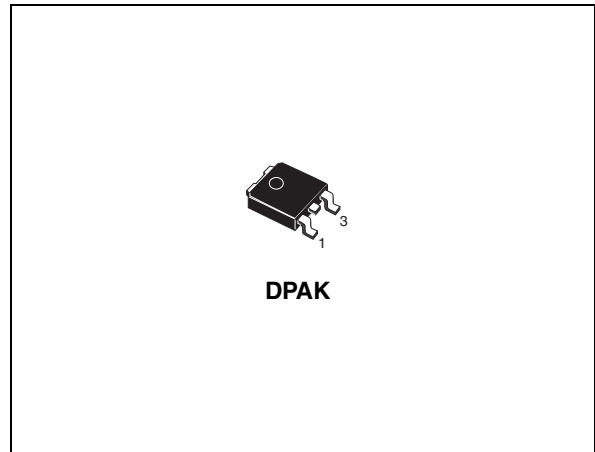


Figure 1. Internal schematic diagram

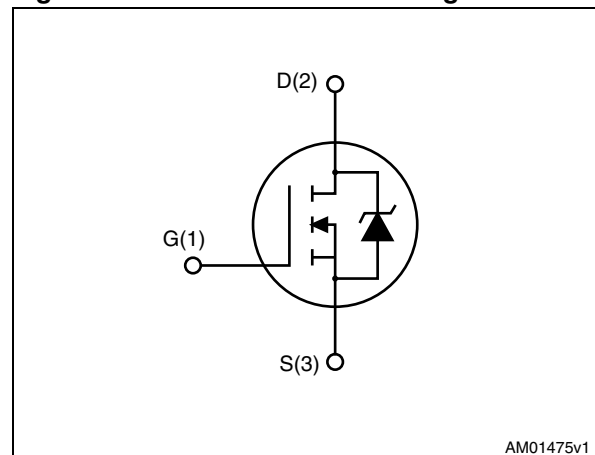


Table 1. Device summary

| Order code | Marking | Packages | Packaging     |
|------------|---------|----------|---------------|
| STD9NM50N  | 9NM50N  | DPAK     | Tape and reel |

Contents

1      **Electrical ratings** ..... 3

2      **Electrical characteristics** ..... 4

        2.1      Electrical characteristics (curves) ..... 6

3      **Test circuits** ..... 8

4      **Package mechanical data** ..... 9

5      **Packaging mechanical data** ..... 12

6      **Revision history** ..... 14



# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

| Symbol         | Parameter                                                         | Value       | Unit               |
|----------------|-------------------------------------------------------------------|-------------|--------------------|
| $V_{GS}$       | Gate-source voltage                                               | $\pm 25$    | V                  |
| $I_D$          | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$  | 5           | A                  |
| $I_D$          | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$ | 3           | A                  |
| $I_{DM}^{(1)}$ | Drain current (pulsed)                                            | 20          | A                  |
| $P_{TOT}$      | Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$           | 45          | W                  |
| $dv/dt^{(2)}$  | Peak diode recovery voltage slope                                 | 15          | V/ns               |
| $T_{stg}$      | Storage temperature                                               | - 55 to 150 | $^{\circ}\text{C}$ |
| $T_j$          | Max. operating junction temperature                               | 150         | $^{\circ}\text{C}$ |

1. Pulse width limited by safe operating area

2.  $I_{SD} \leq 5\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ ,  $V_{Peak} < V_{(BR)DSS}$ ,  $V_{DS}=80\% V_{(BR)DSS}$

**Table 3. Thermal data**

| Symbol         | Parameter                            | Value | Unit                        |
|----------------|--------------------------------------|-------|-----------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 2.78  | $^{\circ}\text{C}/\text{W}$ |
| $R_{thj-pcb}$  | Thermal resistance junction-pcb max  | 50    | $^{\circ}\text{C}/\text{W}$ |

**Table 4. Avalanche characteristics**

| Symbol   | Parameter                                                                                                      | Value | Unit |
|----------|----------------------------------------------------------------------------------------------------------------|-------|------|
| $I_{AR}$ | Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ max)                             | 2     | A    |
| $E_{AS}$ | Single pulse avalanche energy (starting $T_j = 25^{\circ}\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 140   | mJ   |

## 2 Electrical characteristics

( $T_C = 25\text{ }^{\circ}\text{C}$  unless otherwise specified)

**Table 5. On /off states**

| Symbol        | Parameter                                        | Test conditions                                                                       | Min. | Typ. | Max.     | Unit                           |
|---------------|--------------------------------------------------|---------------------------------------------------------------------------------------|------|------|----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage ( $V_{GS} = 0$ )  | $I_D = 1\text{ mA}$                                                                   | 500  |      |          | V                              |
| $I_{DSS}$     | Zero gate voltage drain current ( $V_{GS} = 0$ ) | $V_{DS} = 500\text{ V}$<br>$V_{DS} = 500\text{ V}, T_C = 125\text{ }^{\circ}\text{C}$ |      |      | 1<br>100 | $\mu\text{A}$<br>$\mu\text{A}$ |
| $I_{GSS}$     | Gate-body leakage current ( $V_{DS} = 0$ )       | $V_{GS} = \pm 25\text{ V}$                                                            |      |      | 100      | nA                             |
| $V_{GS(th)}$  | Gate threshold voltage                           | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$                                       | 2    | 3    | 4        | V                              |
| $R_{DS(on)}$  | Static drain-source on resistance                | $V_{GS} = 10\text{ V}, I_D = 2.5\text{ A}$                                            |      | 0.73 | 0.79     | $\Omega$                       |

**Table 6. Dynamic**

| Symbol                              | Parameter                                                               | Test conditions                                                                                          | Min. | Typ.             | Max. | Unit           |
|-------------------------------------|-------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------------|------|------------------|------|----------------|
| $C_{iss}$<br>$C_{oss}$<br>$C_{rss}$ | Input capacitance<br>Output capacitance<br>Reverse transfer capacitance | $V_{DS} = 50\text{ V}, f = 1\text{ MHz},$<br>$V_{GS} = 0$                                                | -    | 364<br>33<br>1.2 | -    | pF<br>pF<br>pF |
| $C_{oss(eq)}^{(1)}$                 | Equivalent output capacitance time related                              | $V_{DS} = 0\text{ to }50\text{ V}, V_{GS} = 0$                                                           | -    | 147.5            | -    | pF             |
| $R_G$                               | Intrinsic gate resistance                                               | $f = 1\text{ MHz open drain}$                                                                            | -    | 5.4              | -    | $\Omega$       |
| $Q_g$<br>$Q_{gs}$<br>$Q_{gd}$       | Total gate charge<br>Gate-source charge<br>Gate-drain charge            | $V_{DD} = 400\text{ V}, I_D = 5\text{ A},$<br>$V_{GS} = 10\text{ V}$<br>(see <a href="#">Figure 13</a> ) | -    | 14<br>3<br>7     | -    | nC<br>nC<br>nC |

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 7. Switching times**

| Symbol       | Parameter           | Test conditions                                                                                                                    | Min. | Typ. | Max | Unit |
|--------------|---------------------|------------------------------------------------------------------------------------------------------------------------------------|------|------|-----|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 250\text{ V}$ , $I_D = 5\text{ A}$ ,<br>$R_G = 4.7\ \Omega$ , $V_{GS} = 10\text{ V}$<br>(see <a href="#">Figure 12</a> ) | -    | 7    | -   | ns   |
| $t_r$        | Rise time           |                                                                                                                                    |      | 4.4  |     | ns   |
| $t_{d(off)}$ | Turn-off-delay time |                                                                                                                                    |      | 25   |     | ns   |
| $t_f$        | Fall time           |                                                                                                                                    |      | 8.8  |     | ns   |

**Table 8. Source drain diode**

| Symbol          | Parameter                     | Test conditions                                                                                                                                              | Min. | Typ. | Max. | Unit          |
|-----------------|-------------------------------|--------------------------------------------------------------------------------------------------------------------------------------------------------------|------|------|------|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                                                              | -    |      | 5    | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                                                              |      |      | 20   | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD} = 5\text{ A}$ , $V_{GS} = 0$                                                                                                                         | -    |      | 1.5  | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 5\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$<br>$V_{DD} = 60\text{ V}$ (see <a href="#">Figure 17</a> )                                        | -    | 187  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                                              |      | 1.3  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                                              |      | 14   |      | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 5\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$<br>$V_{DD} = 60\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$<br>(see <a href="#">Figure 17</a> ) | -    | 224  |      | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                                              |      | 1.5  |      | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                                              |      | 13   |      | A             |

1. Pulse width limited by safe operating area.

2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

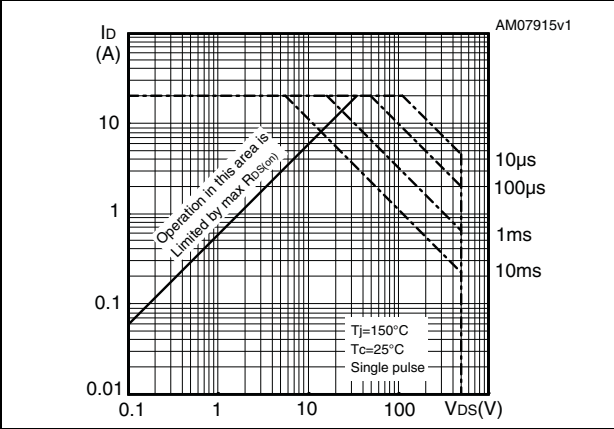


Figure 3. Thermal impedance

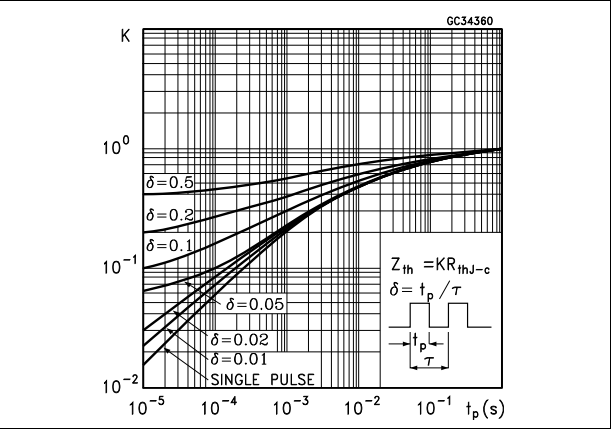


Figure 4. Output characteristics

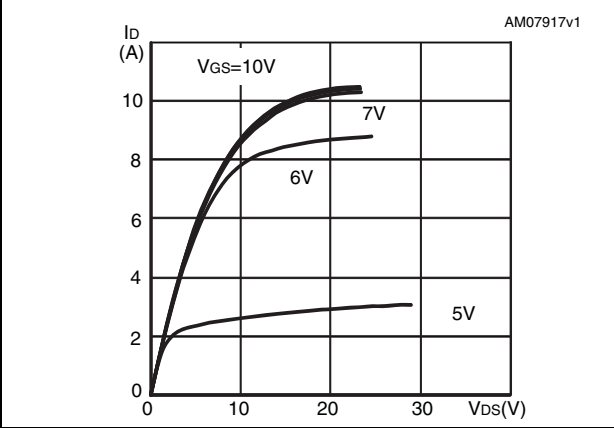


Figure 5. Transfer characteristics

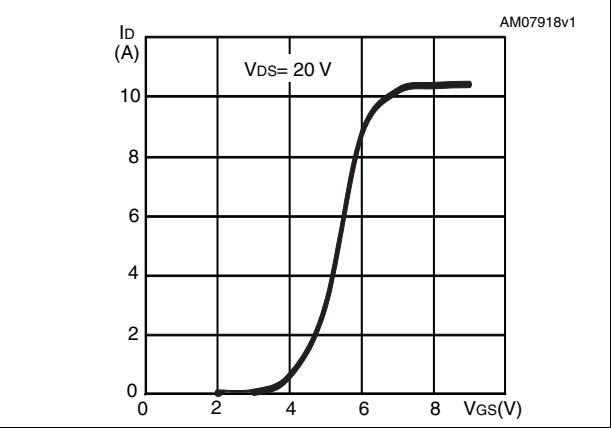


Figure 6. Static drain-source on resistance

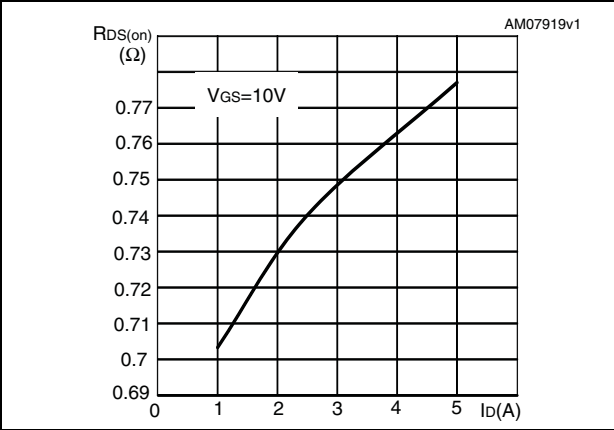


Figure 7. Gate charge vs gate-source voltage

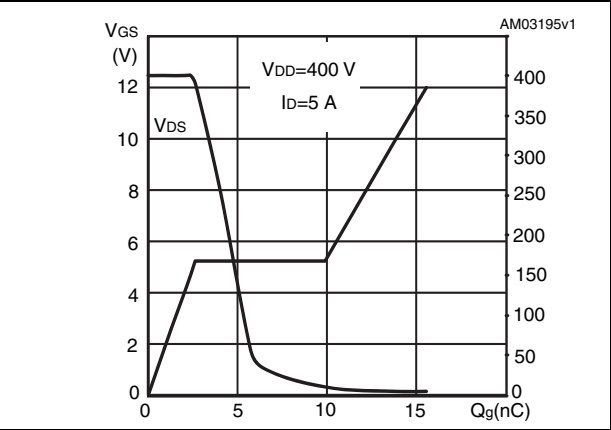


Figure 8. Capacitance variations

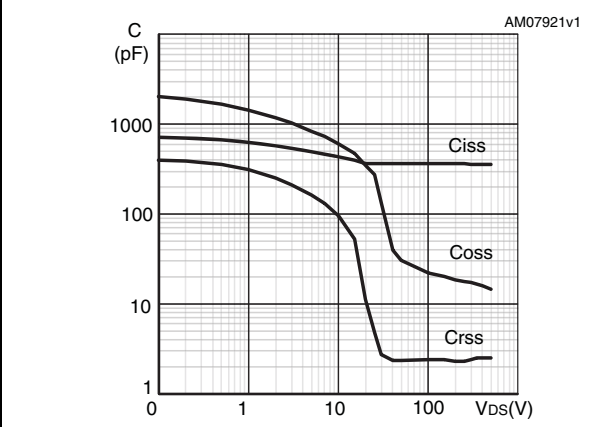


Figure 9. Normalized BV<sub>dss</sub> vs temperature

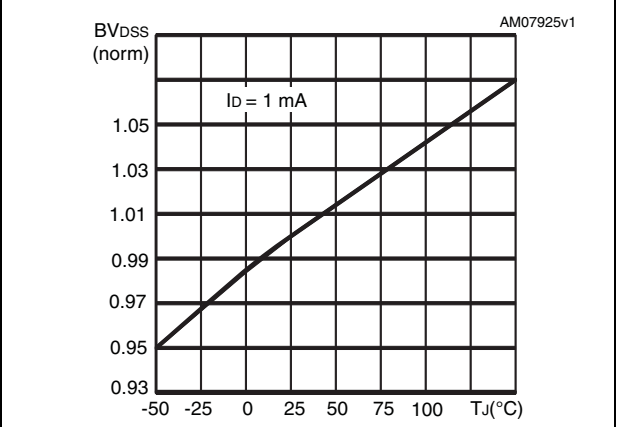


Figure 10. Normalized gate threshold voltage vs temperature

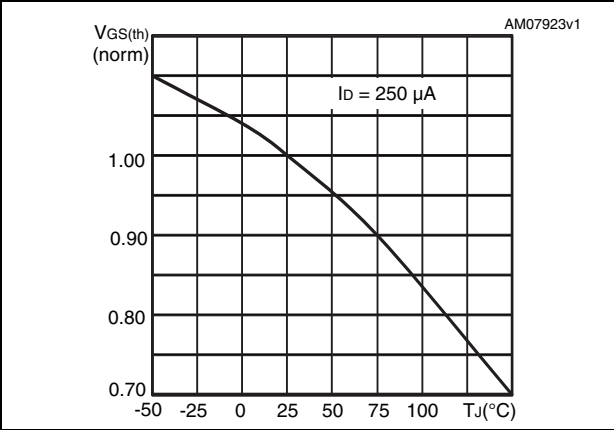
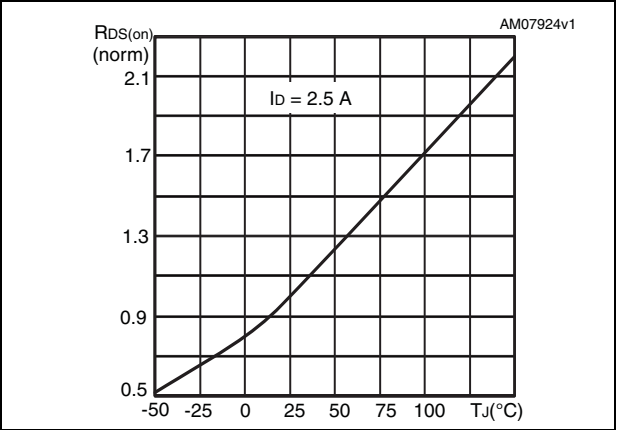
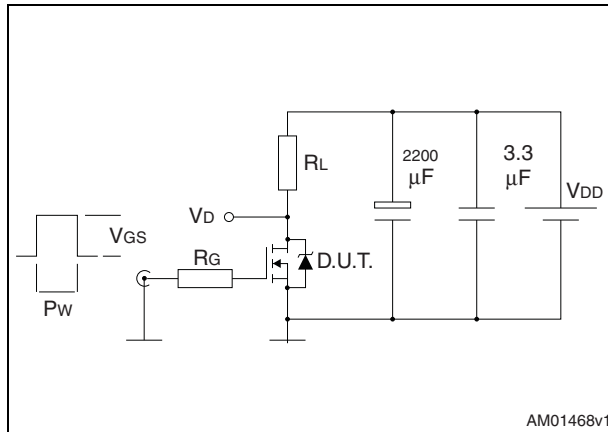


Figure 11. Normalized on resistance vs temperature

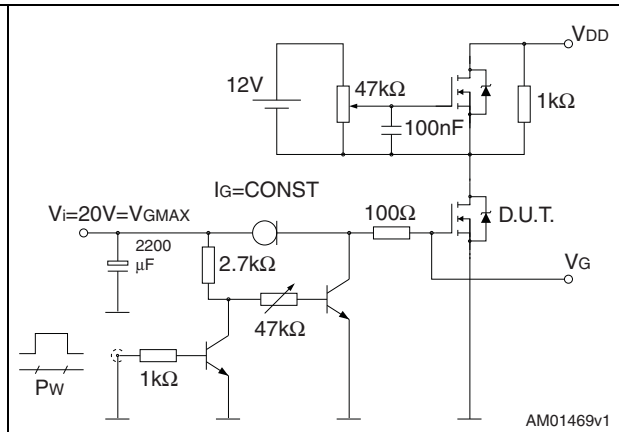


### 3 Test circuits

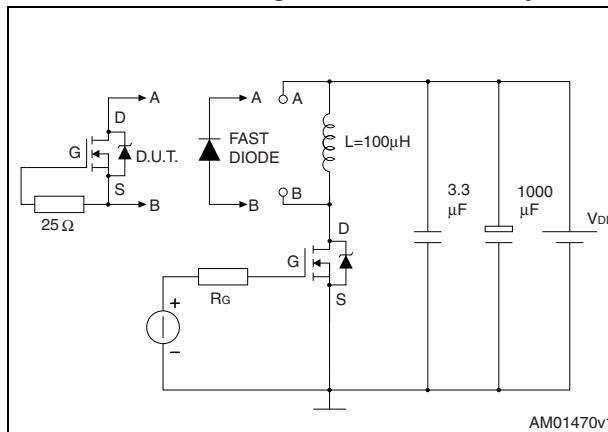
**Figure 12. Switching times test circuit for resistive load**



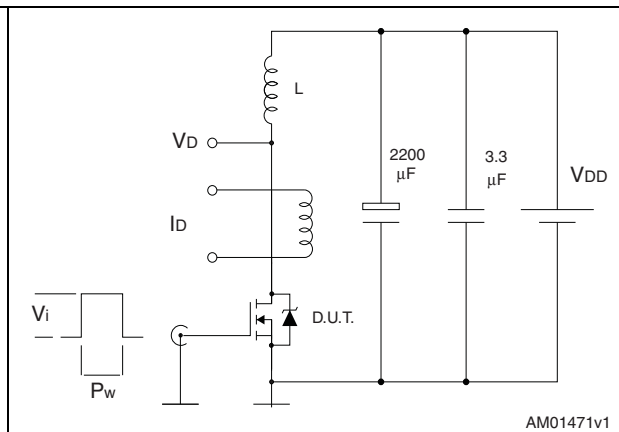
**Figure 13. Gate charge test circuit**



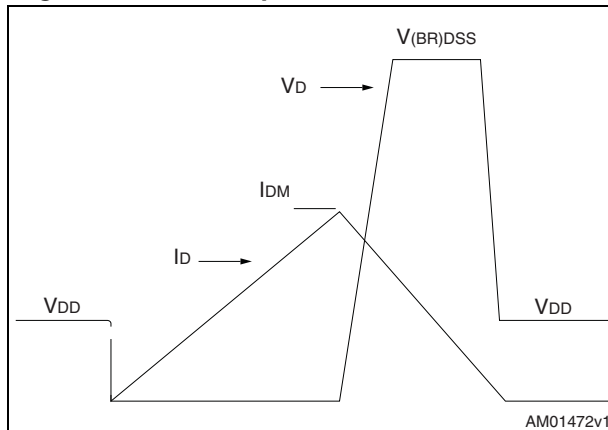
**Figure 14. Test circuit for inductive load switching and diode recovery times**



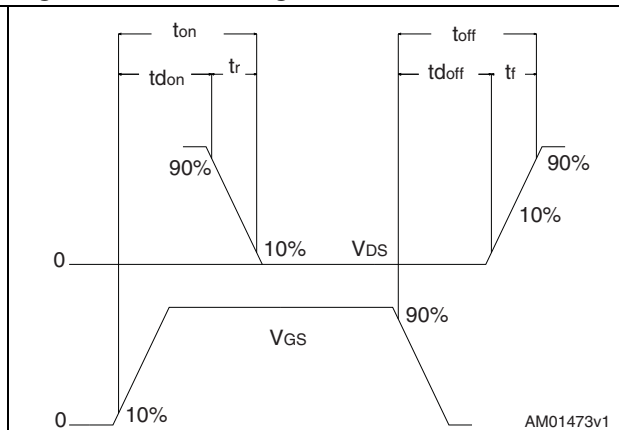
**Figure 15. Unclamped inductive load test circuit**



**Figure 16. Unclamped inductive waveform**



**Figure 17. Switching time waveform**



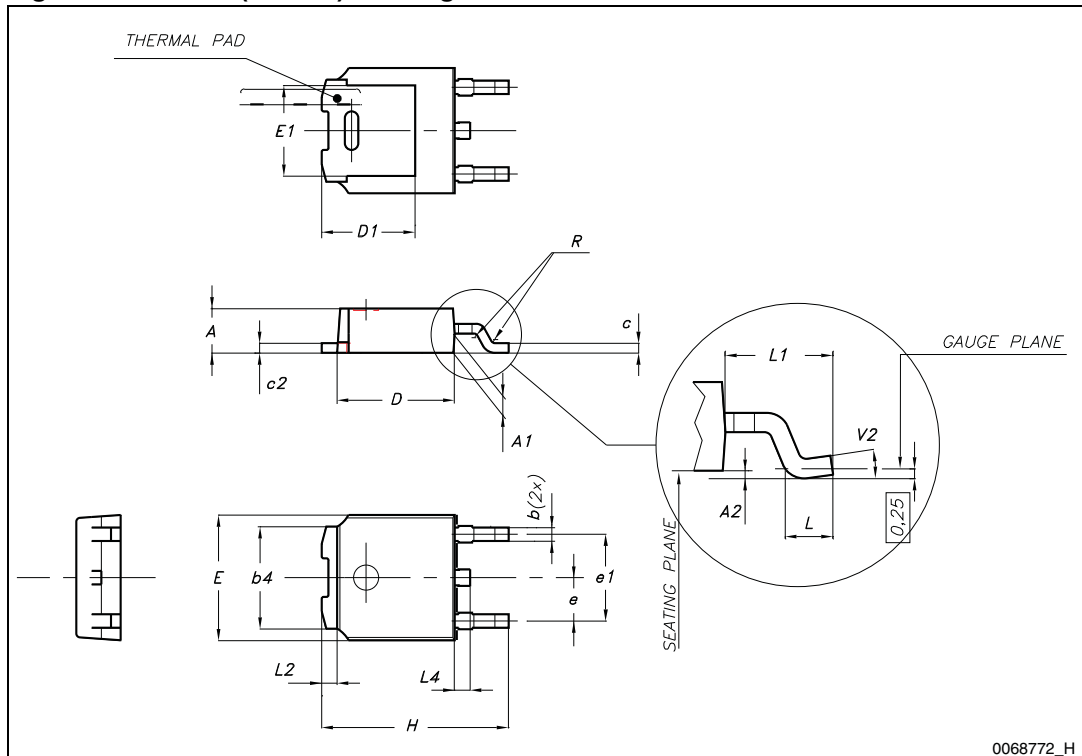
## 4      **Package mechanical data**

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

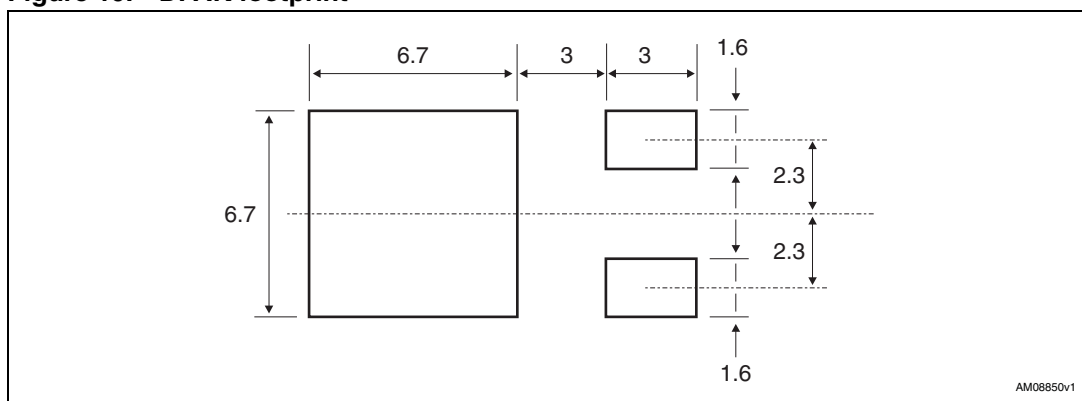
Table 9. DPAK (TO-252) mechanical data

| Dim. | mm   |      |       |
|------|------|------|-------|
|      | Min. | Typ. | Max.  |
| A    | 2.20 |      | 2.40  |
| A1   | 0.90 |      | 1.10  |
| A2   | 0.03 |      | 0.23  |
| b    | 0.64 |      | 0.90  |
| b4   | 5.20 |      | 5.40  |
| c    | 0.45 |      | 0.60  |
| c2   | 0.48 |      | 0.60  |
| D    | 6.00 |      | 6.20  |
| D1   |      | 5.10 |       |
| E    | 6.40 |      | 6.60  |
| E1   |      | 4.70 |       |
| e    |      | 2.28 |       |
| e1   | 4.40 |      | 4.60  |
| H    | 9.35 |      | 10.10 |
| L    | 1    |      | 1.50  |
| L1   |      | 2.80 |       |
| L2   |      | 0.80 |       |
| L4   | 0.60 |      | 1     |
| R    |      | 0.20 |       |
| V2   | 0°   |      | 8°    |

Figure 18. DPAK (TO-252) drawing



0068772\_H

Figure 19. DPAK footprint<sup>(a)</sup>

AM08850v1

a. All dimension are in millimeters

## 5 Packaging mechanical data

Table 10. DPAK (TO-252) tape and reel mechanical data

| Tape |      |      | Reel      |      |      |
|------|------|------|-----------|------|------|
| Dim. | mm   |      | Dim.      | mm   |      |
|      | Min. | Max. |           | Min. | Max. |
| A0   | 6.8  | 7    | A         |      | 330  |
| B0   | 10.4 | 10.6 | B         | 1.5  |      |
| B1   |      | 12.1 | C         | 12.8 | 13.2 |
| D    | 1.5  | 1.6  | D         | 20.2 |      |
| D1   | 1.5  |      | G         | 16.4 | 18.4 |
| E    | 1.65 | 1.85 | N         | 50   |      |
| F    | 7.4  | 7.6  | T         |      | 22.4 |
| K0   | 2.55 | 2.75 |           |      |      |
| P0   | 3.9  | 4.1  | Base qty. |      | 2500 |
| P1   | 7.9  | 8.1  | Bulk qty. |      | 2500 |
| P2   | 1.9  | 2.1  |           |      |      |
| R    | 40   |      |           |      |      |
| T    | 0.25 | 0.35 |           |      |      |
| W    | 15.7 | 16.3 |           |      |      |

Figure 20. Tape for DPAK (TO-252)

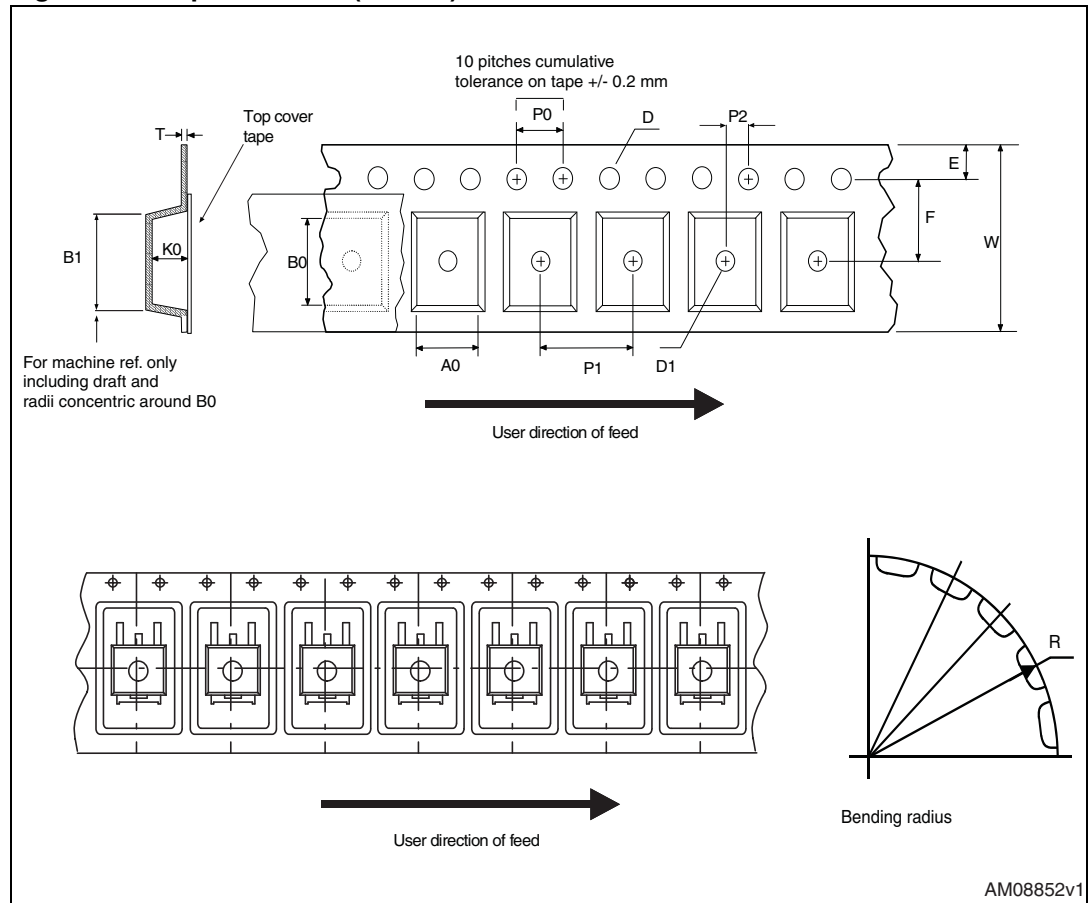
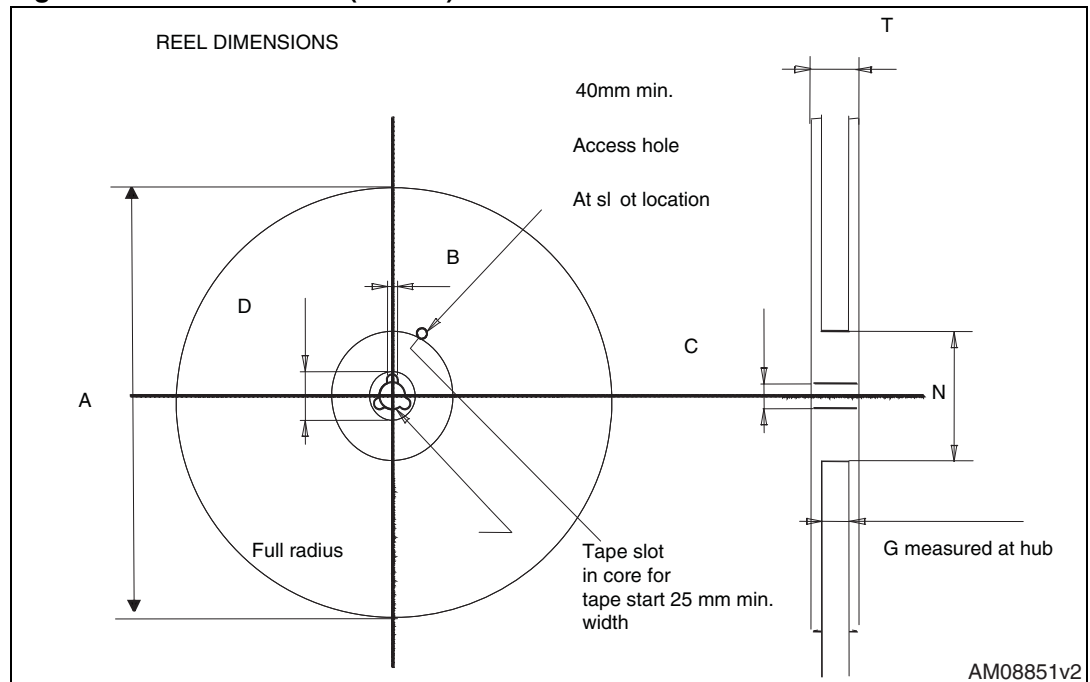


Figure 21. Reel for DPAK (TO-252)



## 6 Revision history

**Table 11. Document revision history**

| Date        | Revision | Changes        |
|-------------|----------|----------------|
| 21-Sep-2011 | 1        | First release. |

**Please Read Carefully:**

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

**UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.**

**UNLESS EXPRESSLY APPROVED IN WRITING BY TWO AUTHORIZED ST REPRESENTATIVES, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.**

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2011 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Philippines - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

[www.st.com](http://www.st.com)

